

Evaluation of the impact of top-off on the ALS users

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Motivation

- Identify issues and mitigate potential problems with top-off
 - Evaluate the impact of the present injection process on various types of user experiments
- Help define the scope of the project

Process

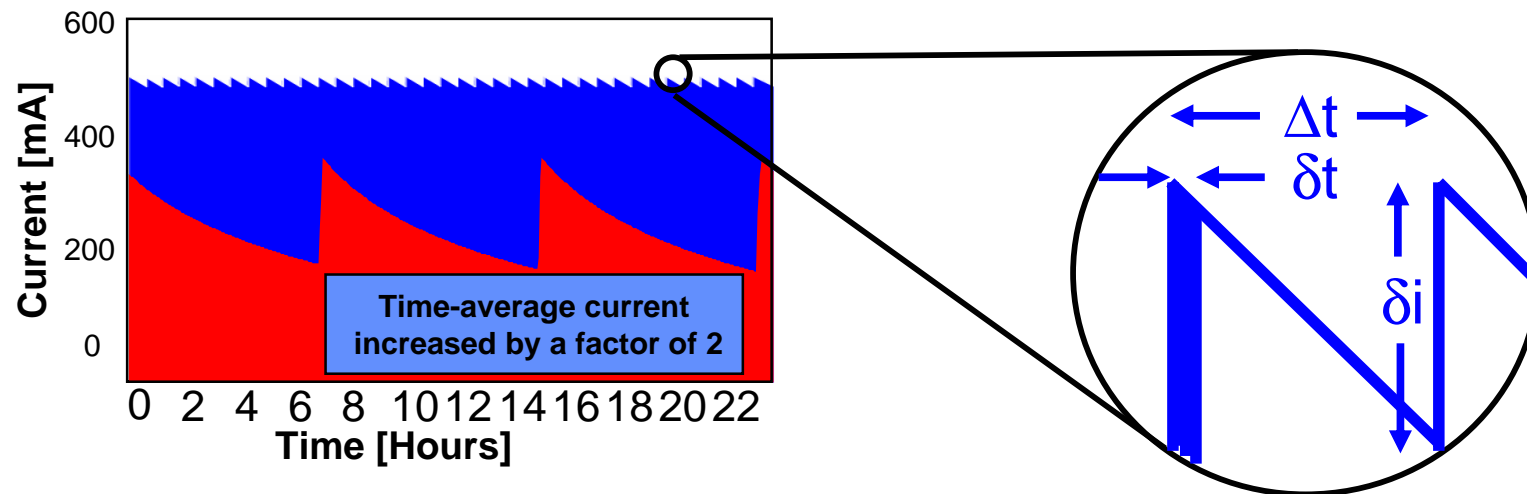
- Experiments with representative user groups
- Discussion of experimental results and top-off parameters in meetings with experiment participants and with the UEC

Issues that were addressed

- Allowable change in current when topping up
- Allowable orbit disturbance during injection
 - Amount and duration
 - Is gating an option?
- Inject equally spaced in time or current drop
 - Inject one pulse or several pulses (burst mode)
- Two bunch mode and camshaft beam cleaning

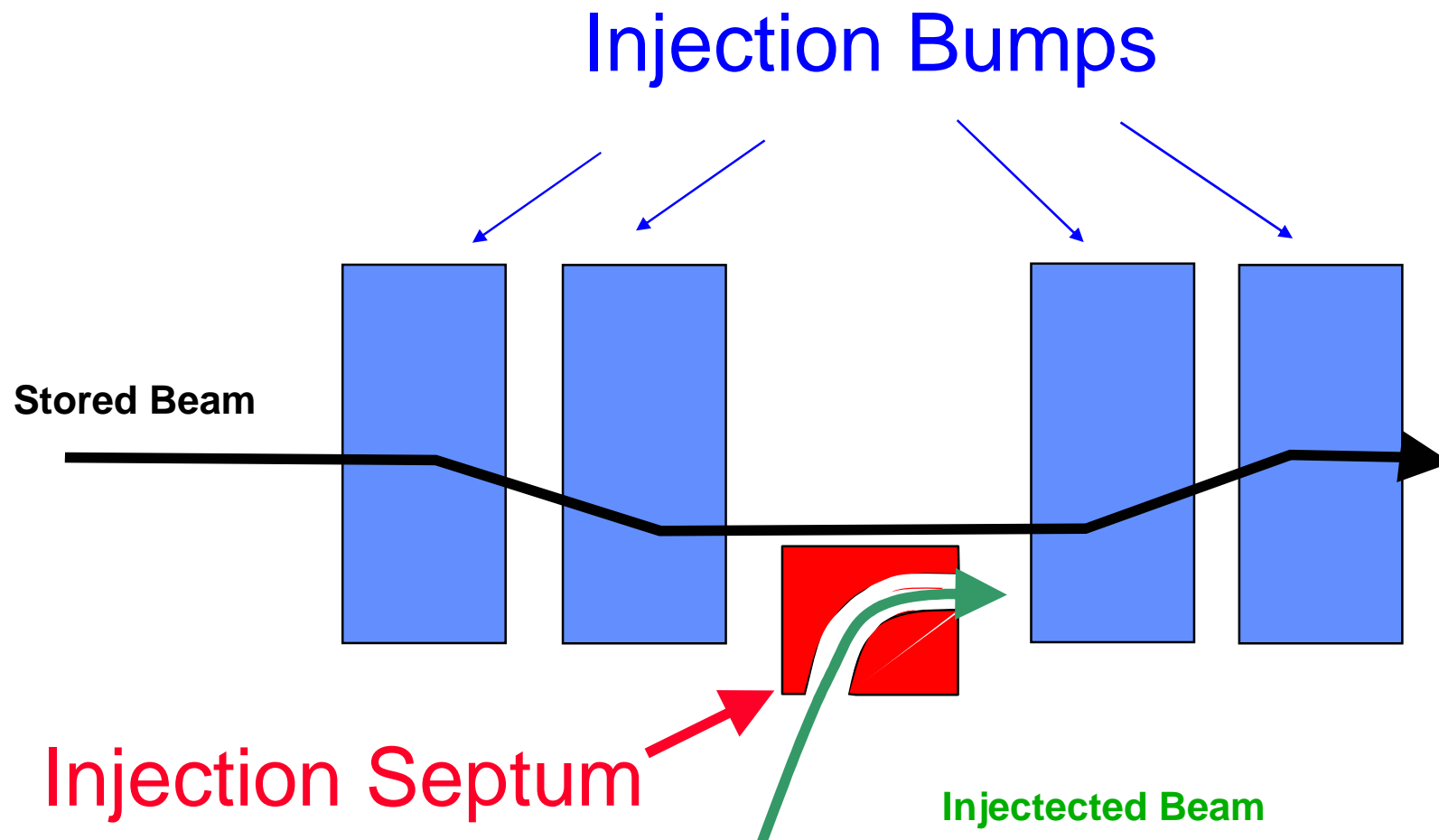
Injection Tests for Top Off

This note records effects observed at various beam lines during injection tests to simulate the closed orbit perturbations expected when the ALS operates in top-off mode. Injection is planned at 1.9GeV with the shutters open, to maintain the current at 500mA.

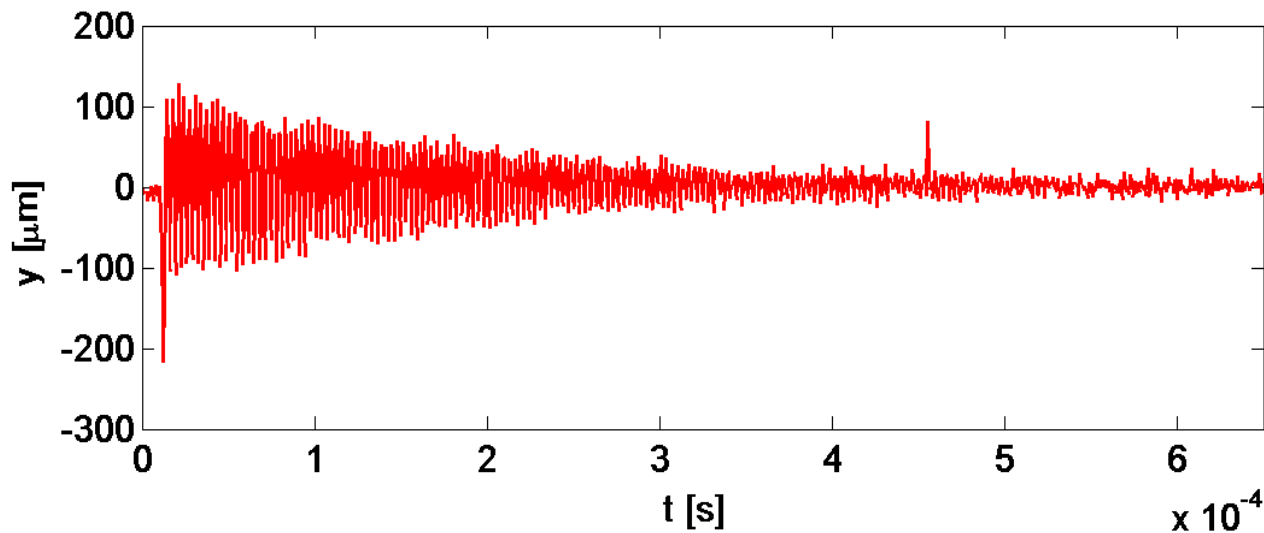
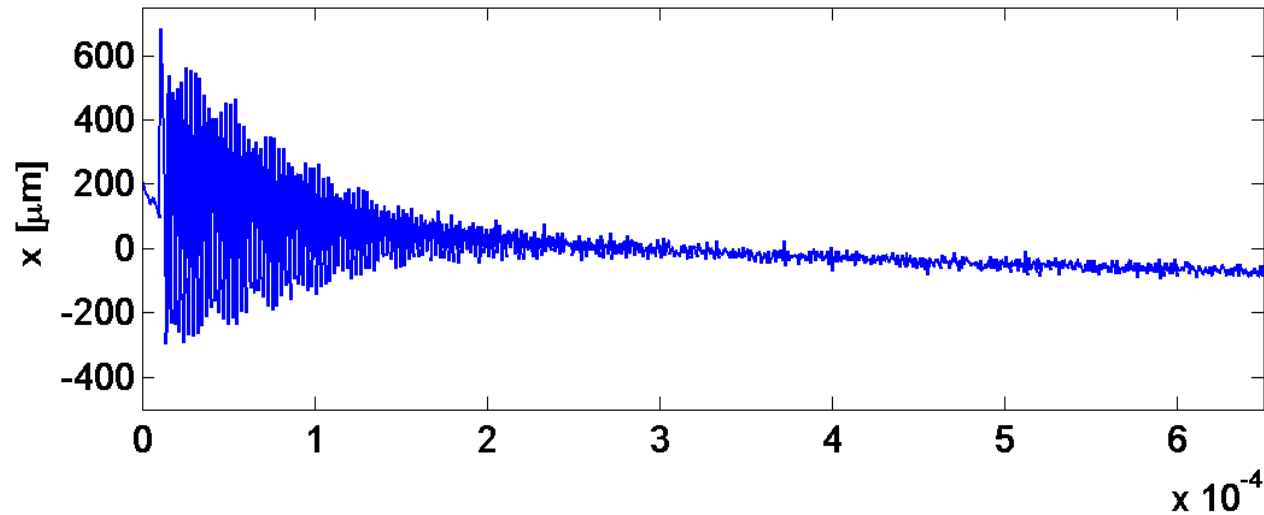


<u>coupling</u>	δi	Δt	δt	ϵ_v	σ_h	σ_v	σ'_h	σ'_v
Operational 03	1.5mA	72.0s	$\leq 50\text{ms}$	150×10^{-12}	298 μm	23 μm	22 μrad	6 μrad
Intermediate	1.5mA	32.0s	$\leq 50\text{ms}$	30×10^{-12}	298 μm	8 μm	22 μrad	3 μrad
Smallest Ever	1.5mA	14.4s	$\leq 50\text{ms}$	5×10^{-12}	298 μm	3 μm	22 μrad	1 μrad

Injection Elements in Straight 1



Transients of injection elements, fast timescale



In terms of
beamsize

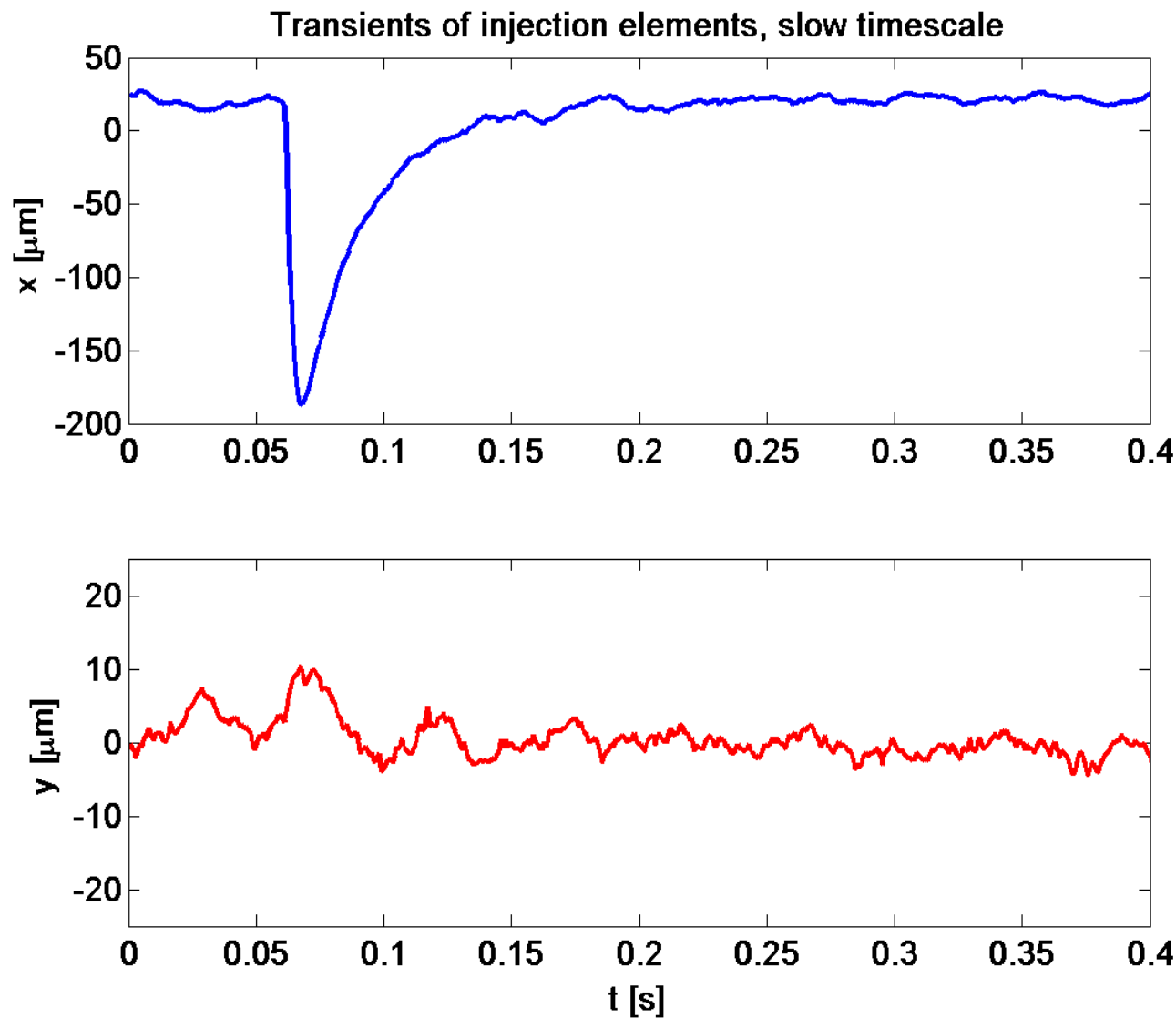
$\sim 1.3 \sigma_x$
peak-to-peak

$\sim 4 \sigma_y$
peak-to-peak

In terms of
beamsize

$\sim 2/3 \sigma_x$
peak

$< 1/3 \sigma_y$
peak





Effects of the inj. bumps and septa

Experimentalists

M. Martin (1.4), A.T. Young and E. Arenholz (4.0), David Kilcoyne (5.3.2), E. Gullikson (6.3.2), Eli Rotenberg (7.0), A. Scholl (7.3), J. Holton (8.3.1), J. Bozek (10.0), M. Marcus (10.3.2), T. Tyliszczak (11.0.2), K. Goldberg (12.0)

Three measurement dates → Participating Beamlines

December 7, 2003 → 5.3.2, 11.0

January 26, 2004 → 1.4, 4.0, 5.3.2, 7.0, 7.3 (PEEM), 8.3.1, 10.3.2, 10.0, 11.0.2

April 19, 2004 → 1.4, 4.0, 6.3.2, 11.0.2, 12.0

Meeting on February 13, 2004

Summarize the results of the December 7, 2003 and January 26, 2004 measurements

David Attwood, John Bozek, Erik Gullikson, James Holton, Zahid Hussain, David Kilcoyne, Mark Le Gros, Dennis Lindle, Alastair MacDowell, Mathew Marcus, Howard Padmore, Andreas Scholl, Christoph Steier, Tony Warwick, Tony Young

Presentation to the UEC on March 2, 2004



Injection Tests for Top Off

19 April 2004

Three test conditions were run, with various beam lines looking at the effects:

Condition 1 normal operation.

Condition 2 injection bumps and septa pulsing every 30 seconds.

Condition 3 injection bumps only, every 30 seconds.

Best estimate is that the injection for top-off will be approximately every 30 seconds. The septum magnets are known to leak field and affect the position of the stored beam, if this problem is solved then condition 3 will best represent top-off operation.

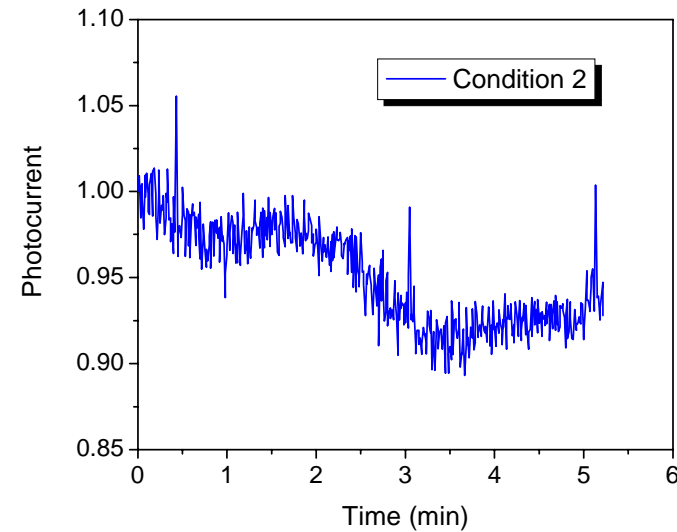
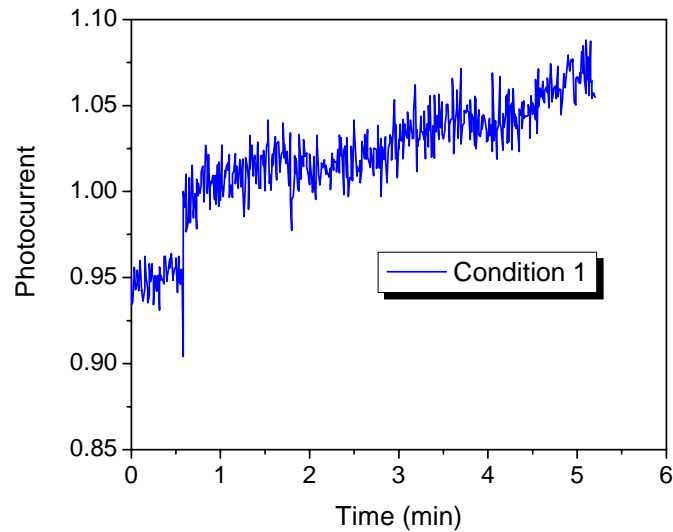
No beam was actually injected during these tests. Observed variations in experiment count rates are due to transient distortions of the closed orbit.

Beam lines 10.3.2 microXAS, saw no effects.

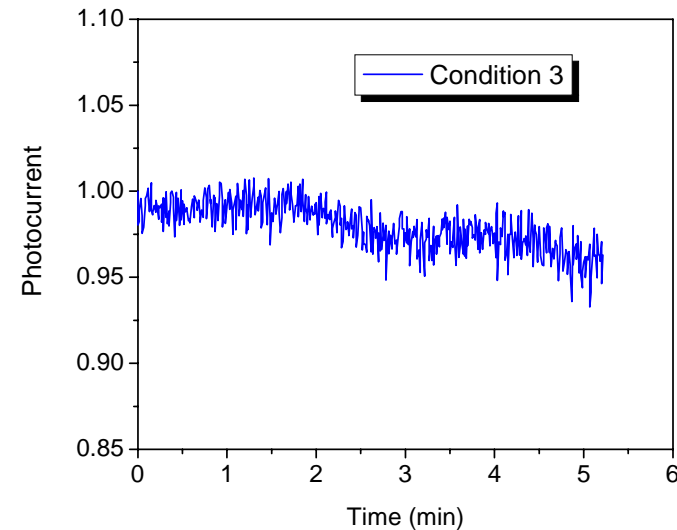
Beam lines 4.0 and 6.3.2 monitored the beam line flux and saw counting glitches under condition 2 that may be due to injection transients.

Beam line 1.4 (FT IR spectroscopy) saw definite glitches during instrument scanning under conditions 2 and 3.

Beam line 11.0.2 (STXM) saw definite glitches during instrument scanning under condition 2.

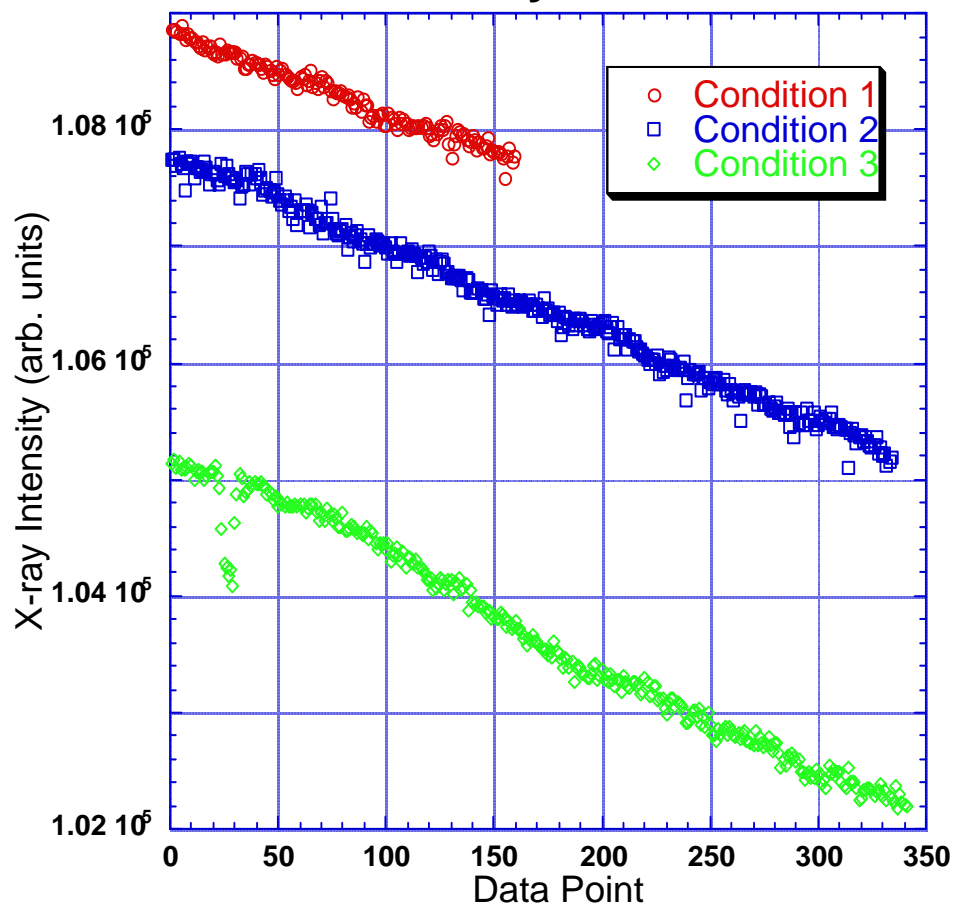


Signal measured after vertical slit offset in X by 160 microns from the center of the beam in the endstation. One point every 0.6 sec.

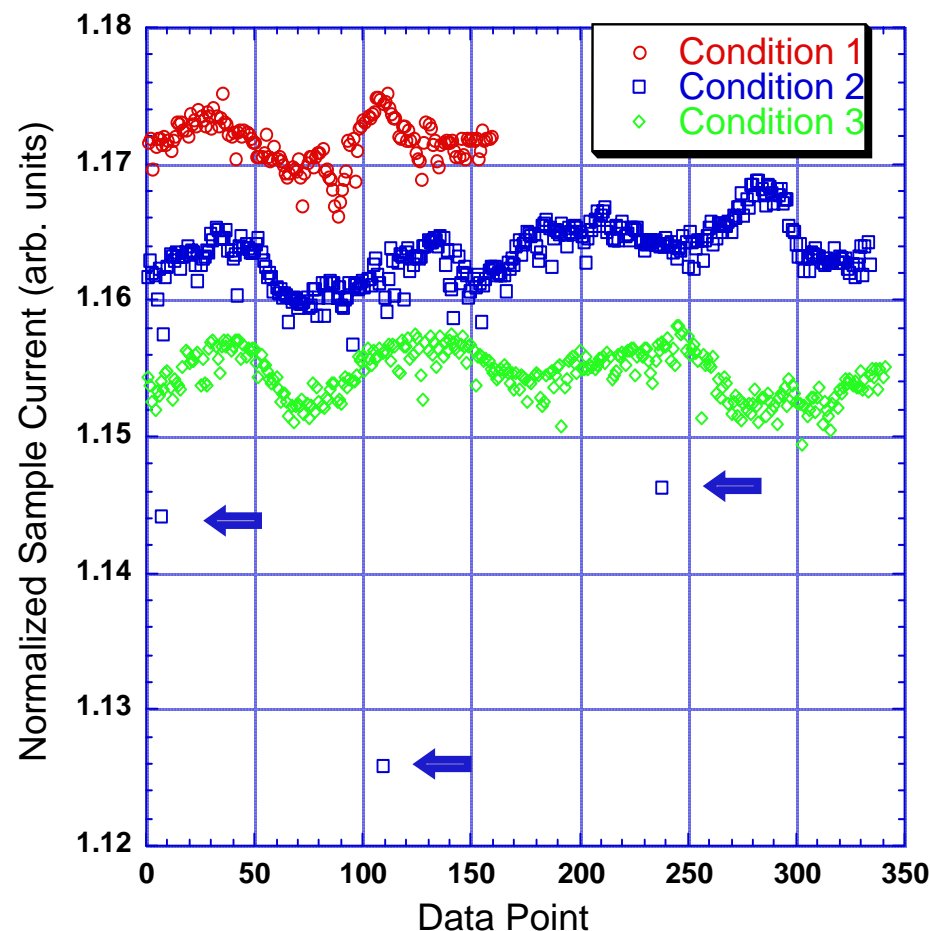


Beamline 4.0.2

Intensity Monitor



Normalized Absorption

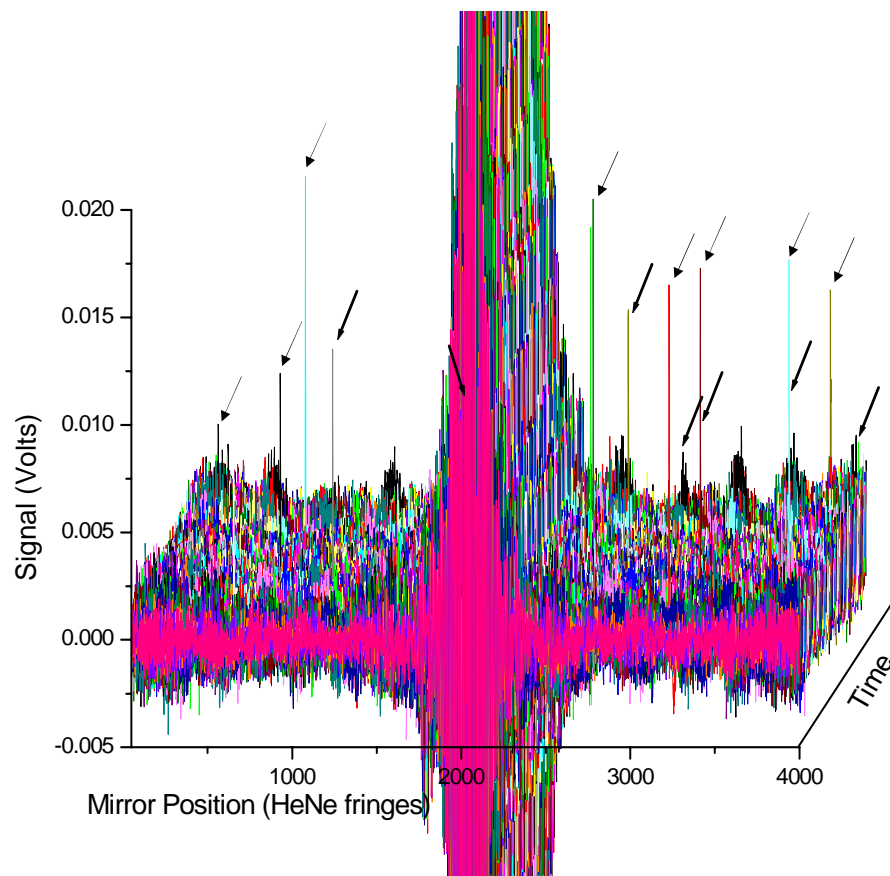


- Absorption measured at Cu L_3 peak at 932 eV, 1 sec avg, every 3.75 sec
- Condition 2 Intensity is somewhat noisier
- Condition 2 Absorption shows several large deviations, indicative of a small photon energy shift, and consistent with an average injection period of 32.4 sec
- Actual injection time data is not available

Summary:

- Simulated injections every ~30 seconds.
- I performed a “typical” mapping experiment, 32 averages (11.7 seconds) per point, + 7.5 seconds of dead time moving sample stage to next point. 160 total spectra during mapping test.

I see “spikes” in a number of scans throughout the test map:



No simulated injections

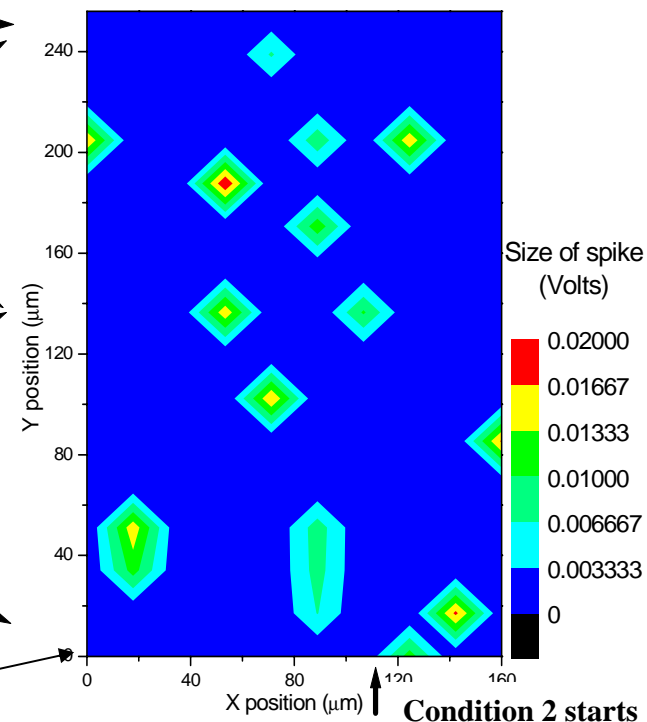
Condition 3

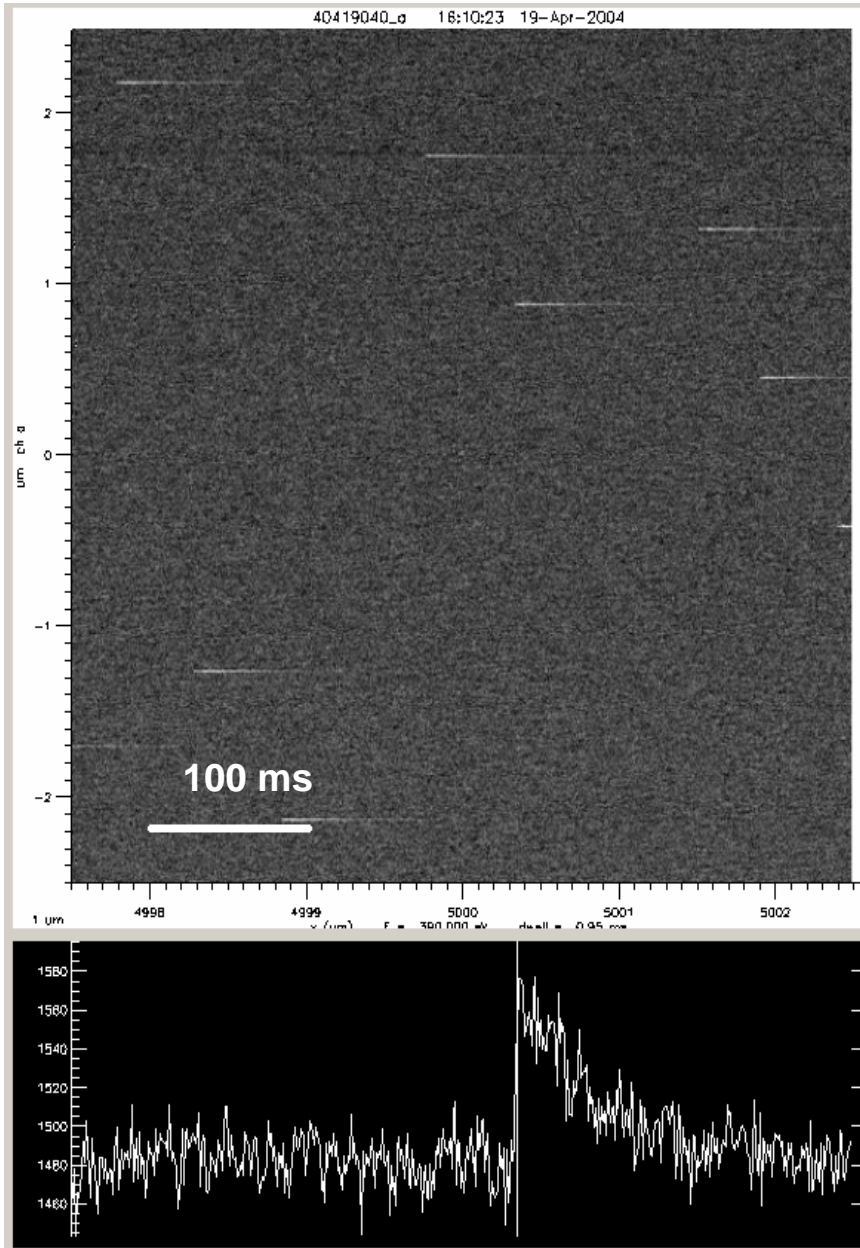
Simulated injections with bumps and big septum off

Condition 2

Simulated injections with bumps and big septum on

Condition 1 (briefly)





During this test the sensitivity of the STXM 11.0.2 was much smaller than during the previous test (Dec 03). Figure shows the influence of the injection (condition 2) - about 5 % of the signal for about 200 ms.

During condition 3 - the perturbation was within the noise level for 0.1, 0.2 and 1ms/pt image acquisition at 2 energies (1st and 3rd EPU harmonic).

Spectra acquisition at the exit slit (testing the beamline not STXM) did not show any significant perturbation.



Injection Tests for Top Off

LSBL 709

Dec/Jan 03/04

Seven test conditions were run, with various beam lines looking at the effects:

Condition 1 40mA no bumps or septa

Condition 2 bumps on and septa on, pulsing at 1Hz

Condition 3 feed-back H=off V=on

Condition 4 feed-back H=off V=off

Condition 5 400mA feed-back H=on V=off

Condition 6 400mA feed-back slow-orbit=off

Condition 7 bumps on and septa off

This is the original set of tests and the conclusions are similar to those drawn in April 04. The STXM tests were more sensitive on this occasion and definite glitches were apparent even with the septa turned off.

No beam was actually injected during these tests. Observed variations in experiment count rates are due to transient distortions of the closed orbit.

Beam lines 10.3.2 microXAS, 7.0 photoemission, 7.3.3 PEEM and 8.3.1 PX, saw no effects.

Beam lines 4.0 monitored the beam line flux and saw counting glitches under condition 2 that may be due to injection transients.

Beam line 1.4 (FT IR spectroscopy) saw definite glitches during instrument scanning under conditions 2 through 5.

Beam line 11.0.2 (STXM) saw definite glitches during instrument scanning under conditions 2 through 6, with greatly reduced transients under condition 7. Beam line 5.3.2 (STXM) saw the same, with variations depending on the feedback configuration.

Top-up tests: 10.3.2 Jan 04

*We cannot
see any
effect here* LSBL 709

Experiments:

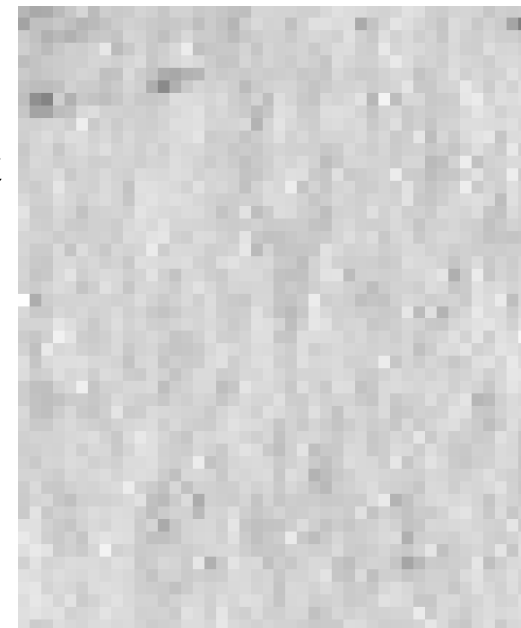
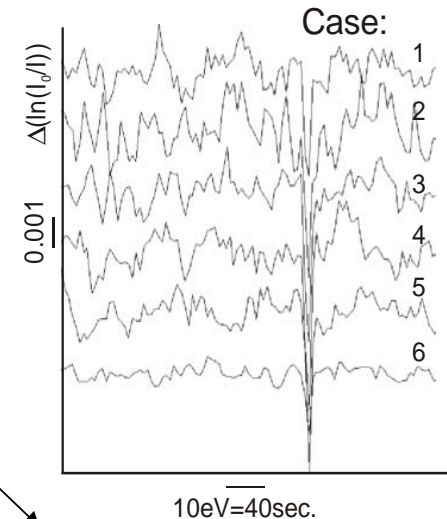
1. EXAFS on Ni foil starting at 9keV, transmission and fluorescence
2. Mapping on same Ni foil.

Executive summary: Nothing happened!

Cautions:

EXAFS: Count time was 4 sec/pt, so each point had the same number of blips, so even if blips affected the signal, we wouldn't see it. Real life: 30sec between blips; so a blip every 3-8 points.

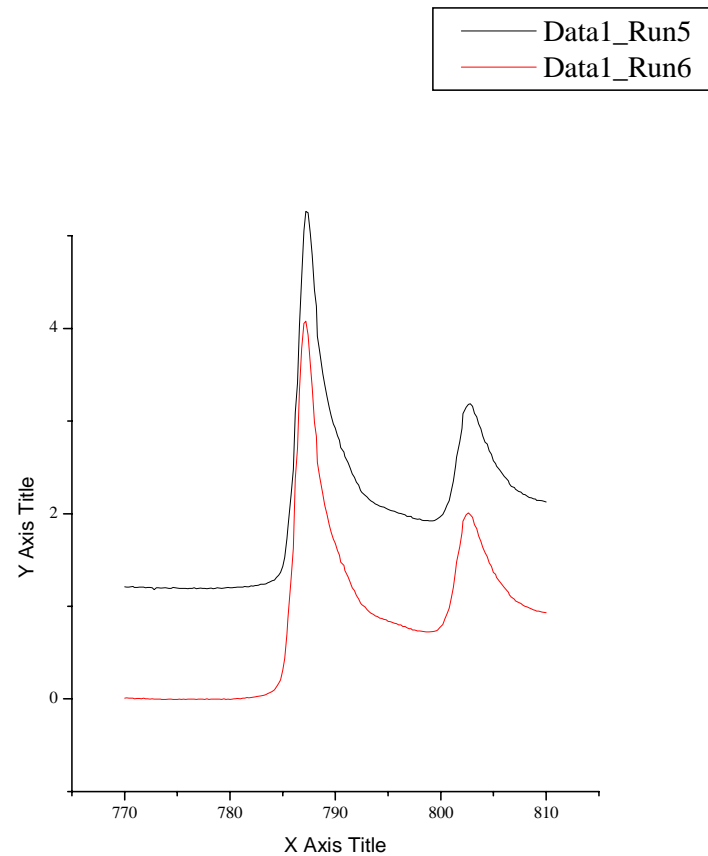
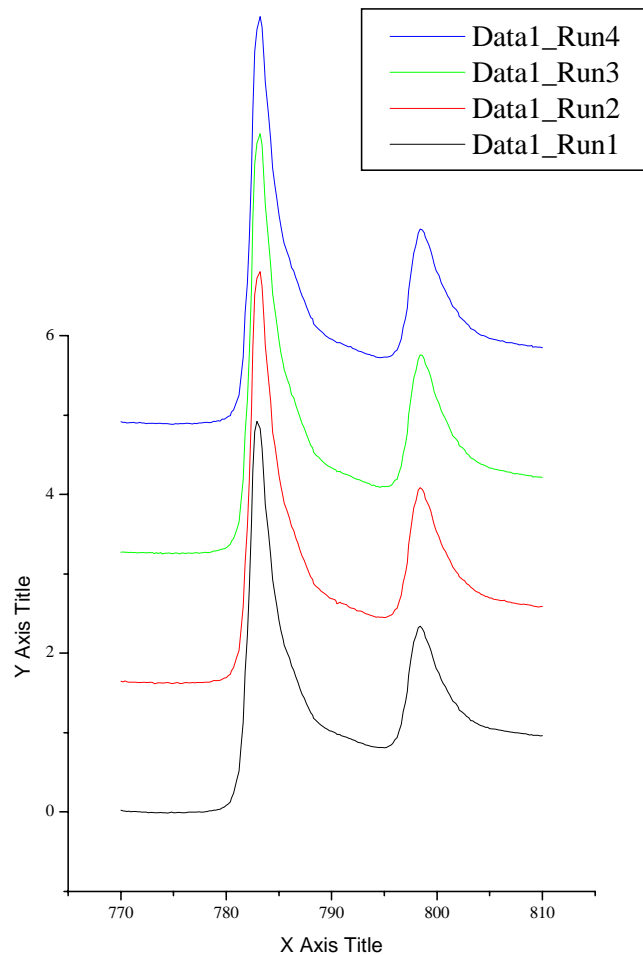
Mapping: Sample was inhomogeneous, which could have hidden the blips. Blips would have been 1-pixel excursions, several/line.



Top-up tests: 7.3.3 Jan 04

*We cannot see
any effect here*
LSBL 709

Typical Co NEXAFS spectra measured with PEEM-2 on 30x30 μm^2 area
Exposure time per point: 2s



No increase in noise is apparent.



PX data in top-off mode, beam line 8.3

LSBL 709
*We cannot see
any effect here*

case	exposure	R _{merge}	R _{anom}	I/sd	Patt	FOM	FOMDM	CC
1	1.00	4.3%	4.6%	29.0	6.77	0.274	0.746	0.4800
2	1.02	4.1%	4.6%	29.5	5.65	0.280	0.673	0.4958
3	1.04	4.3%	4.6%	27.7	6.10	0.267	0.729	0.4955
4	1.05	4.2%	4.6%	28.4	6.19	0.268	0.661	0.4704
5	0.10	4.8%	4.6%	26.3	5.97	0.270	0.751	0.4735
5a	0.90	4.2%	4.5%	29.2	5.71	0.278	0.671	0.4735
6	0.11	4.7%	4.6%	26.8	7.06	0.268	0.665	0.5036
6a	0.93	4.2%	4.5%	29.6	5.72	0.284	0.701	0.4982

All data sets had the same dose: 2×10^6 Ph/um²

the "a" data sets used an Al attenuator to normalize the exposure time

Exposure: the shutter-open time used for 100 images

Rmerge: standard error of equivalent diffraction spot intensities

Ranom: difference between Friedel mates

I/sd: signal-to-noise ration

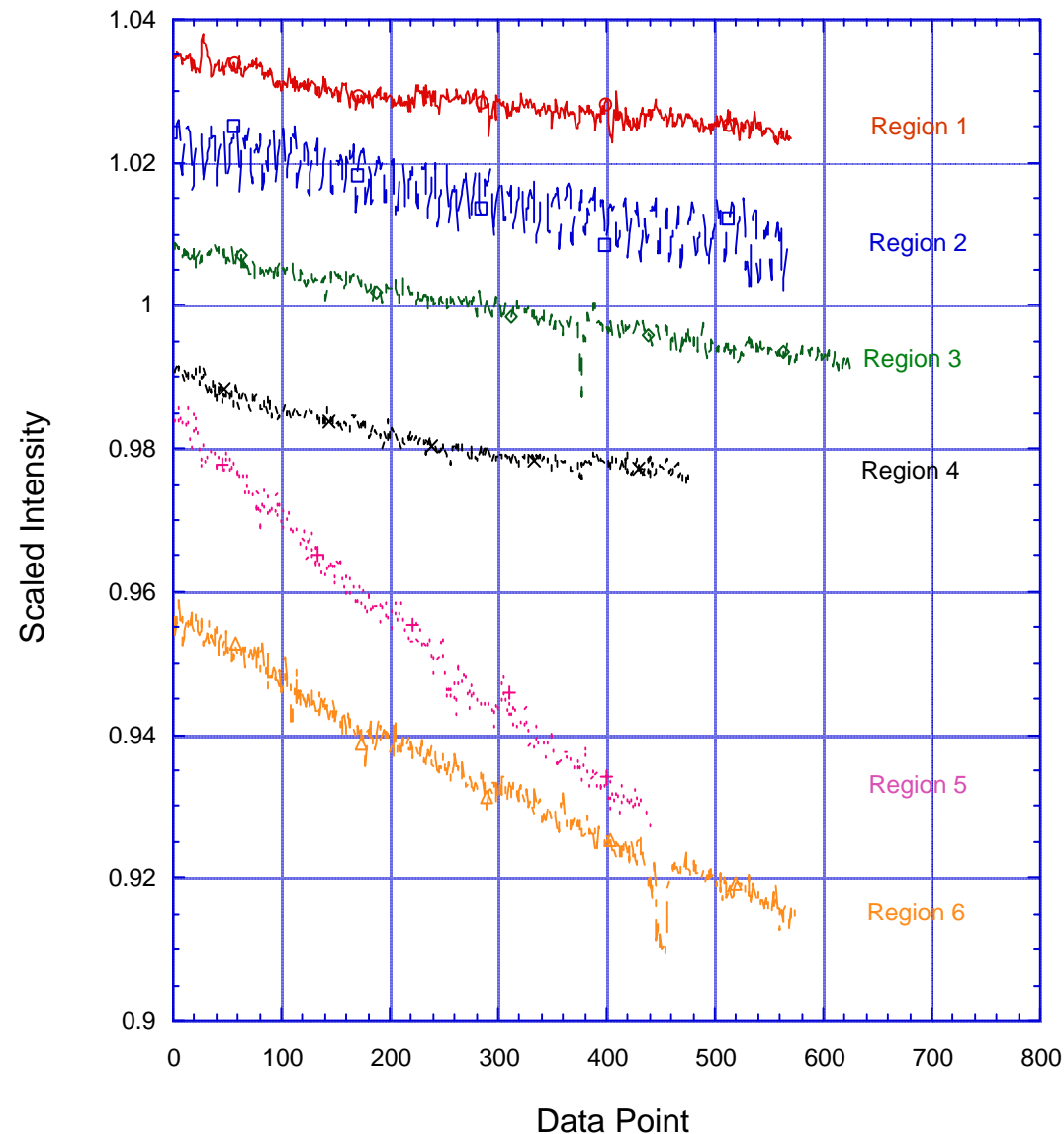
Patt: height/sigma for non-origin Patterson peak

FOM: estimated cosine of phase error

FOMDM: FOM after density modification

CC: correlation coefficient of experimental map to model

Top Off Mode Injection Test: BL 4.0 1/26/04



‘condition 2’ = septum-on we can see intensity fluctuations

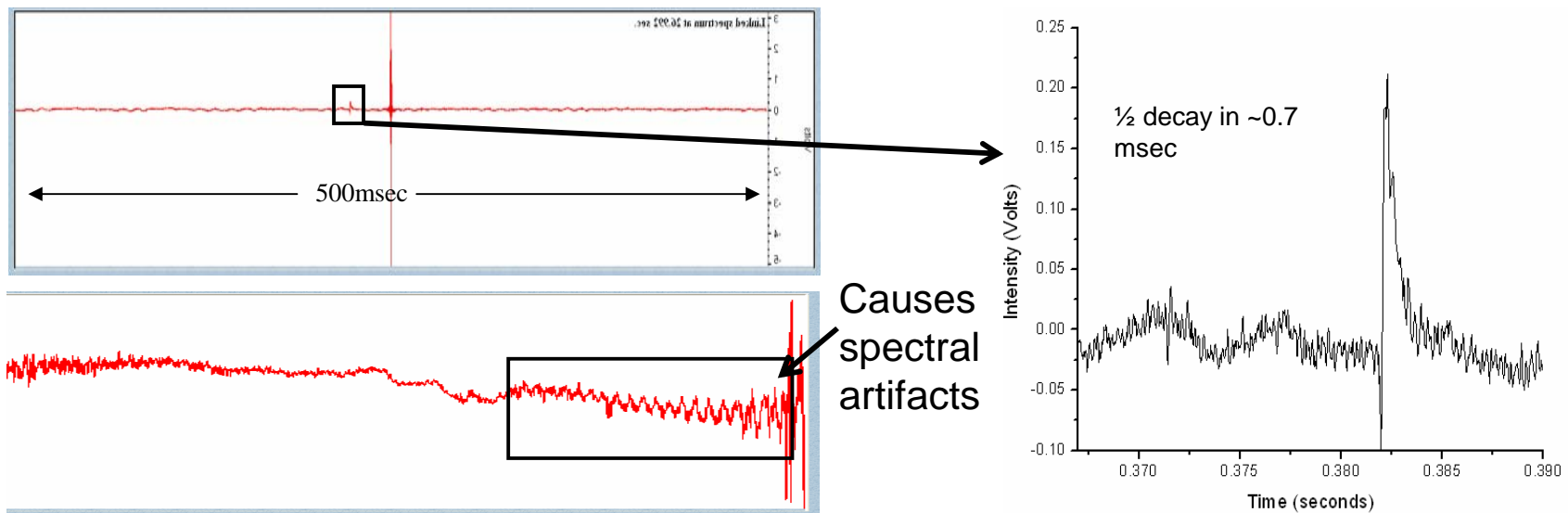
Intensity of the x-rays was determined by measuring the photo-current from a gold mesh

Each data point was integrated for 1 second using a picoammeter and a V/F converter

Each region (condition) was scaled to unity and offset for clarity

Summary:

In conditions 2-5 (injection septum and/or bumps on) we observed brief signal glitches in measured interferograms. Not seen in conditions 1 or 6 (no injection).

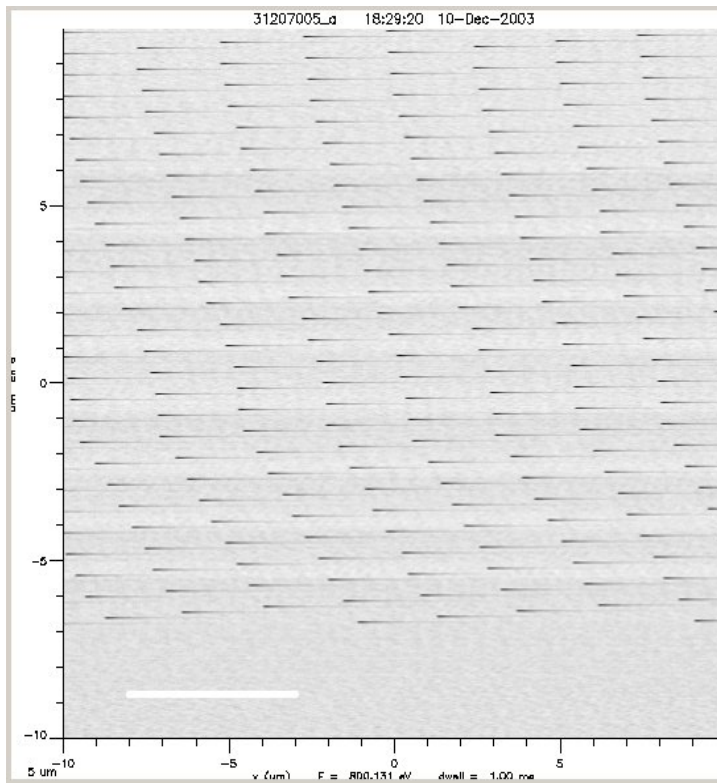


- The typical user averages many spectra, so this will “wash out” into worse Signal to Noise.
- Or we should look for a way to have the software/hardware reject scans when the injection bumps are on.

Condition	Current	S/N
1	40	1470
2	38.3	1243
3	37.6	956
4	36.9	1108
5	387	3467
6	370	3662

“Injection” test 7 Dec 2003

Recorded STXM images



STXM 11.0.2

Undulator, entrance slit-less beam line designed with insensitivity to vertical beam motion, sensitive to horizontal beam motion.

Condition 6 feed-back slow-orbit=off

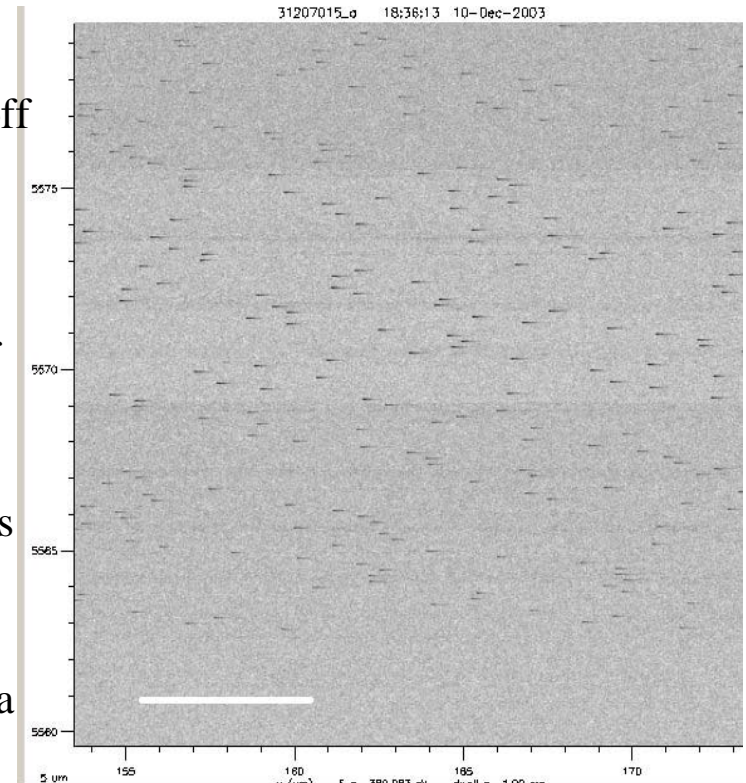
Condition 5 feed-back H=on V=off

Condition 4 feed-back H=off V=off

Condition 3 feed-back H=off V=on

Condition 2 bumps and septa on

Condition 1
No bumps or septa



STXM 5.3.2

Bend magnet, collecting part of the fan, sensitive to vertical beam motion.

Horizontal scale is 500 ms



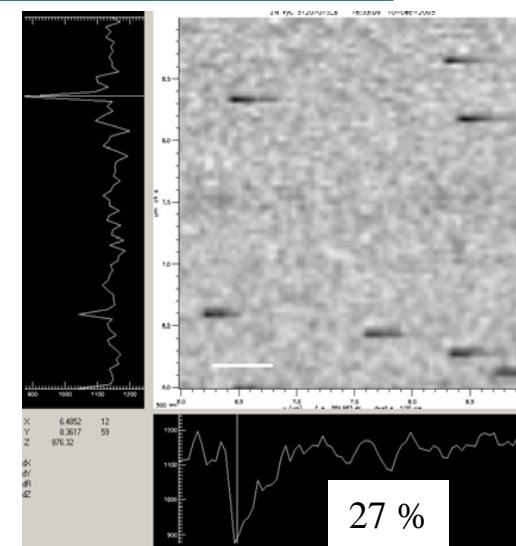
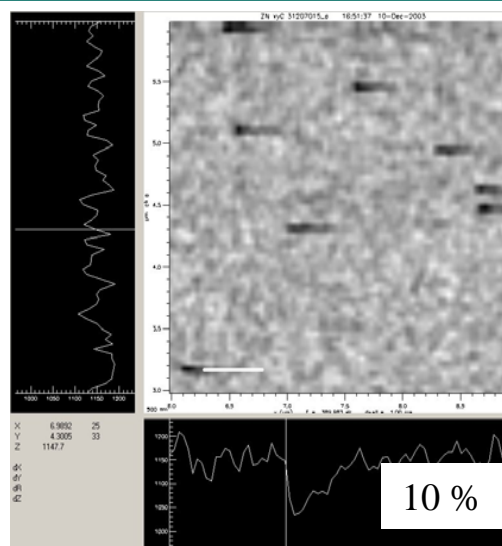
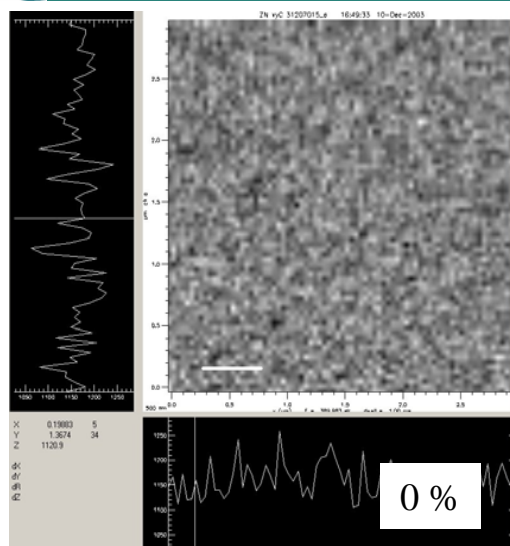
“Injection” tests 7Dec 2003 STXM 5.3.2

LSBL 709

Condition 1
No bumps or septa

Condition 2 bumps
and septa on

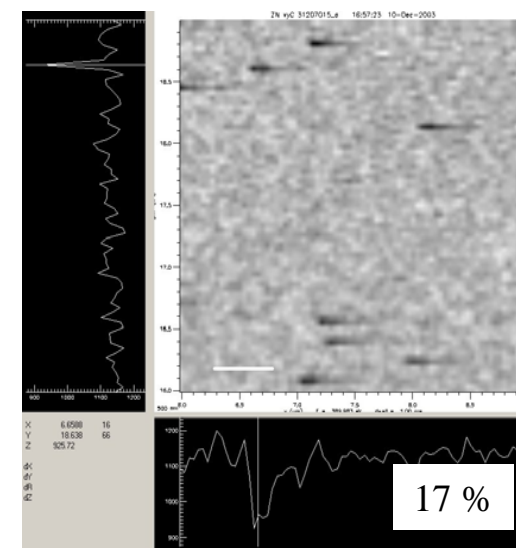
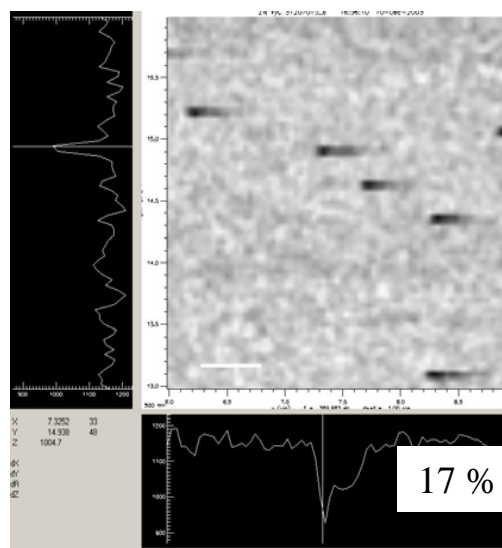
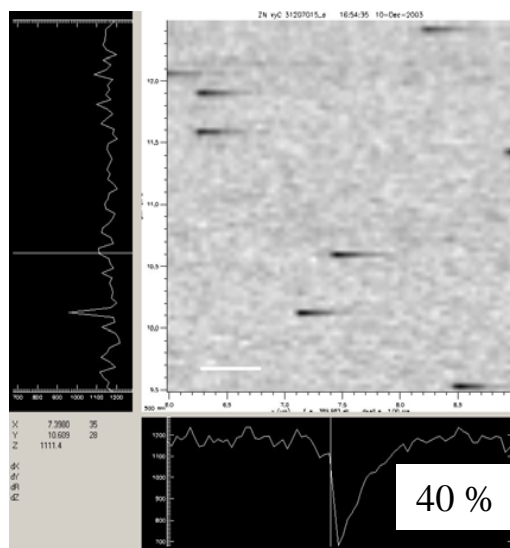
Condition 3 feed-
back H=off V=on



Condition 4 feed-
back H=off V=off

Condition 5 feed-
back H=on V=off

Condition 6 feed-
back slow-orbit=off



Horizontal scale is 75 ms



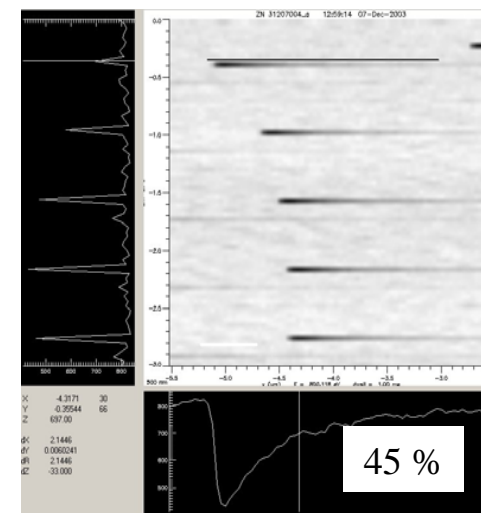
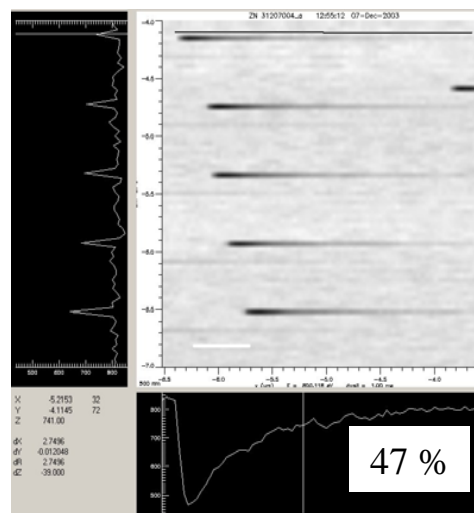
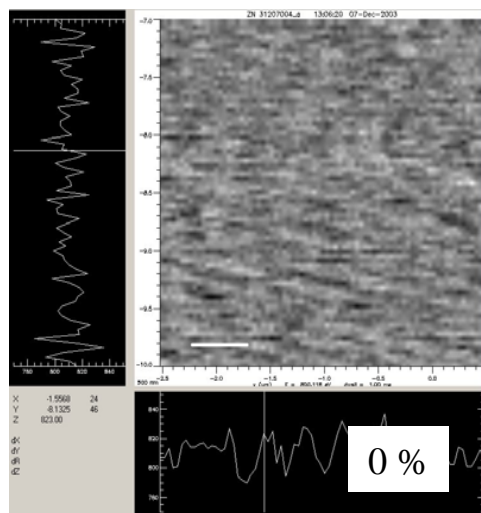
“Injection” tests 7Dec 2003 STXM 11.0.2 zoom-in

LSBL 709

Condition 1
No bumps or septa

Condition 2 bumps
and septa on

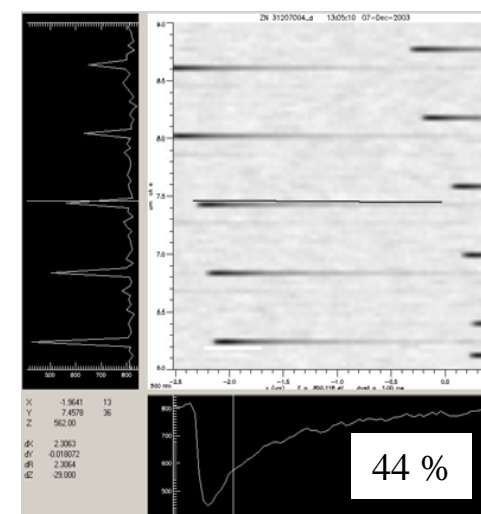
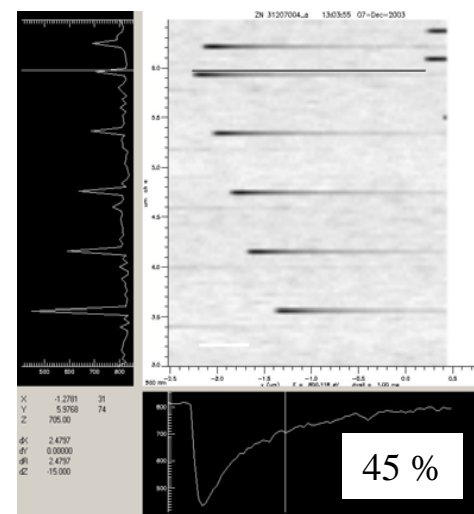
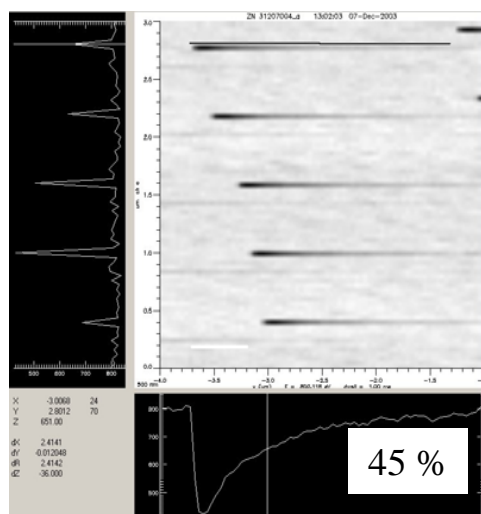
Condition 3 feed-
back H=off V=on



Condition 4 feed-
back H=off V=off

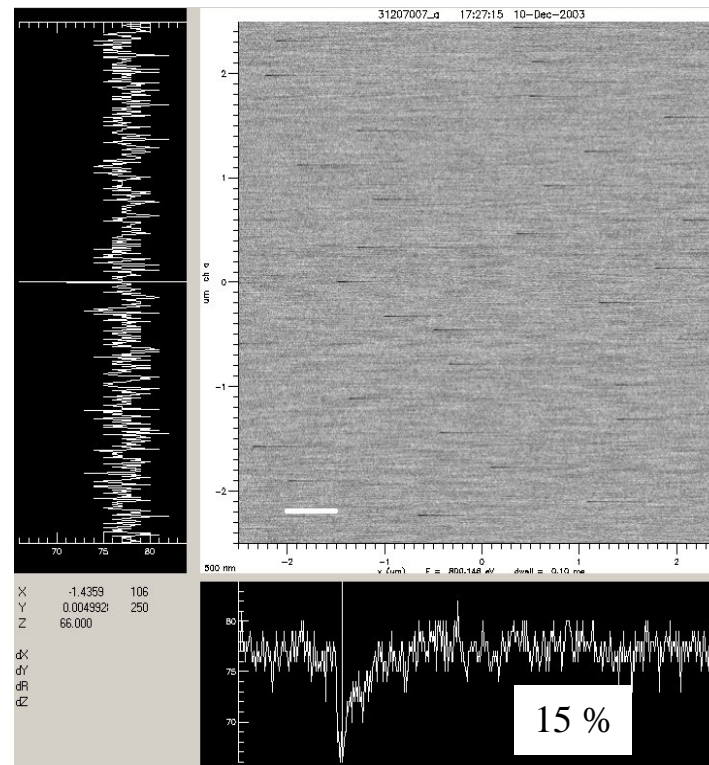
Condition 5 feed-
back H=on V=off

Condition 6 feed-
back slow-orbit=off



Horizontal scale is 75 ms

Recorded image



Horizontal scale is 60 ms



Summary

- Most experiments did not see the injection transients
- The most sensitive experimental techniques were microscopes with short integration times – in particular STXM (5.3.2 and 11.0.2), IR (1.4.3)
 - For these techniques gating may be a good option and seems not to be too difficult
- Beamline 4.0 also sensitive to the Septum
 - Planned improvements in the Septum should be sufficient

Other issues addressed

- Those requiring gating would like “single shot” injection (i.e. no burst mode)
- Users not very sensitive to bunch-to-bunch current variations
- Users would like to incorporate injection bunch cleaning in the project in order to have cleaner camshaft and 2-bunch top-off operation